

Search Notes

Application/Control No.

10/760,555

Examiner

CongVan Tran

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	410 411 414.1	8/19/2006	CT
340	5.82 5.85	8/19/2006	CT
	5.81 5.52	8/19/2006	CT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR